### NXP USA Inc. - SPC5602PEF0MLH6 Datasheet





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#### Details

Product Status	Active
Core Processor	e200z0h
Core Size	32-Bit Single-Core
Speed	64MHz
Connectivity	CANbus, LINbus, SCI, SPI
Peripherals	DMA, POR, PWM, WDT
Number of I/O	45
Program Memory Size	256KB (256K x 8)
Program Memory Type	FLASH
EEPROM Size	4K x 16
RAM Size	20K x 8
Voltage - Supply (Vcc/Vdd)	3V ~ 5.5V
Data Converters	A/D 16x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	64-LQFP
Supplier Device Package	64-LQFP (10x10)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/spc5602pef0mlh6

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	Feature	MPC5601P	MPC5602P	
FlexPWM (puls	e-width modulation) channels	No	8 (capture capability not supported)	
Analog-to-digita	Il converter (ADC)	1 (10-bit, 1	6 channels)	
LINFlex		1 (1 × Master/Slave)	2 (1 × Master/Slave, 1 × Master only)	
DSPI (deserial	serial peripheral interface)	1	3	
CRC (cyclic red	undancy check) unit	Yes		
Junction tempe	unction temperature sensor No			
JTAG controller		Y	es	
Nexus port cont	troller (NPC)	Yes (Nexu	us Class 1)	
Supply	Digital power supply	3.3 V or 5 V single supp	ly with external transistor	
	Analog power supply	3.3 V or 5 V		
	Internal RC oscillator	16 MHz		
	External crystal oscillator	4–40 MHz		
Packages		64 LQFP 100 LQFP		
Temperature	Standard ambient temperature	_40 to	125 °C	

#### Table 1. MPC5602P device comparison (continued)

<sup>1</sup> Each FlexCAN module has 32 message buffers.

<sup>2</sup> One FlexCAN module can act as a safety port with a bit rate as high as 8 Mbit/s at 64 MHz.

## 1.4 Block diagram

Figure 1 shows a top-level block diagram of the MPC5602P MCU. Table 1 summarizes the functions of the blocks.



\_\_\_\_\_

Block	Function
Analog-to-digital converter (ADC)	Multi-channel, 10-bit analog-to-digital converter
Boot assist module (BAM)	Block of read-only memory containing VLE code which is executed according to the boot mode of the device
Clock generation module (MC_CGM)	Provides logic and control required for the generation of system and peripheral clocks
Controller area network (FlexCAN)	Supports the standard CAN communications protocol
Cross triggering unit (CTU)	Enables synchronization of ADC conversions with a timer event from the eMIOS or from the PIT
Crossbar switch (XBAR)	Supports simultaneous connections between two master ports and three slave ports; supports a 32-bit address bus width and a 32-bit data bus width
Cyclic redundancy check (CRC)	CRC checksum generator
Deserial serial peripheral interface (DSPI)	Provides a synchronous serial interface for communication with external devices
Enhanced direct memory access (eDMA)	Performs complex data transfers with minimal intervention from a host processor via " <i>n</i> " programmable channels
Enhanced timer (eTimer)	Provides enhanced programmable up/down modulo counting
Error correction status module (ECSM)	Provides a myriad of miscellaneous control functions for the device including program-visible information about configuration and revision levels, a reset status register, wakeup control for exiting sleep modes, and optional features such as information on memory errors reported by error-correcting codes
External oscillator (XOSC)	Provides an output clock used as input reference for FMPLL_0 or as reference clock for specific modules depending on system needs
Fault collection unit (FCU)	Provides functional safety to the device
Flash memory	Provides non-volatile storage for program code, constants and variables
Frequency-modulated phase-locked loop (FMPLL)	Generates high-speed system clocks and supports programmable frequency modulation
Interrupt controller (INTC)	Provides priority-based preemptive scheduling of interrupt requests
JTAG controller	Provides the means to test chip functionality and connectivity while remaining transparent to system logic when not in test mode
LINFlex controller	Manages a high number of LIN (Local Interconnect Network protocol) messages efficiently with a minimum of CPU load
Mode entry module (MC_ME)	Provides a mechanism for controlling the device operational mode and mode transition sequences in all functional states; also manages the power control unit, reset generation module and clock generation module, and holds the configuration, control and status registers accessible for applications
Periodic interrupt timer (PIT)	Produces periodic interrupts and triggers
Peripheral bridge (PBRIDGE)	Is the interface between the system bus and on-chip peripherals
Power control unit (MC_PCU)	Reduces the overall power consumption by disconnecting parts of the device from the power supply via a power switching device; device components are grouped into sections called "power domains" which are controlled by the PCU



- Frequency-modulated PLL
  - Modulation enabled/disabled through software
  - Triangle wave modulation
- Programmable modulation depth (±0.25% to ±4% deviation from center frequency): programmable modulation frequency dependent on reference frequency
- Self-clocked mode (SCM) operation

### 1.5.10 Main oscillator

The main oscillator provides these features:

- Input frequency range: 4–40 MHz
- Crystal input mode or oscillator input mode
- PLL reference

### 1.5.11 Internal RC oscillator

This device has an RC ladder phase-shift oscillator. The architecture uses constant current charging of a capacitor. The voltage at the capacitor is compared by the stable bandgap reference voltage.

The RC oscillator provides these features:

- Nominal frequency 16 MHz
- $\pm 5\%$  variation over voltage and temperature after process trim
- Clock output of the RC oscillator serves as system clock source in case loss of lock or loss of clock is detected by the PLL
- RC oscillator is used as the default system clock during startup

### 1.5.12 Periodic interrupt timer (PIT)

The PIT module implements these features:

- 4 general-purpose interrupt timers
- 32-bit counter resolution
- Clocked by system clock frequency
- Each channel usable as trigger for a DMA request

### 1.5.13 System timer module (STM)

The STM implements these features:

- One 32-bit up counter with 8-bit prescaler
- Four 32-bit compare channels
- Independent interrupt source for each channel
- Counter can be stopped in debug mode

### 1.5.14 Software watchdog timer (SWT)

The SWT has the following features:

- 32-bit time-out register to set the time-out period
- Programmable selection of window mode or regular servicing



The BAM provides the following features:

- Serial bootloading via FlexCAN or LINFlex
- Ability to accept a password via the used serial communication channel to grant the legitimate user access to the non-volatile memory

### 1.5.18 Error correction status module (ECSM)

The ECSM provides a myriad of miscellaneous control functions regarding program-visible information about the platform configuration and revision levels, a reset status register, a software watchdog timer, wakeup control for exiting sleep modes, and information on platform memory errors reported by error-correcting codes and/or generic access error information for certain processor cores.

The Error Correction Status Module supports a number of miscellaneous control functions for the platform. The ECSM includes these features:

- Registers for capturing information on platform memory errors if error-correcting codes (ECC) are implemented
- For test purposes, optional registers to specify the generation of double-bit memory errors are enabled on the MPC5602P.

The sources of the ECC errors are:

- Flash memory
- SRAM

### 1.5.19 Peripheral bridge (PBRIDGE)

The PBRIDGE implements the following features:

- Duplicated periphery
- Master access privilege level per peripheral (per master: read access enable; write access enable)
- Write buffering for peripherals
- · Checker applied on PBRIDGE output toward periphery
- Byte endianess swap capability

### 1.5.20 Controller area network (FlexCAN)

The MPC5602P MCU contains one controller area network (FlexCAN) module. This module is a communication controller implementing the CAN protocol according to Bosch Specification version 2.0B. The CAN protocol was designed to be used primarily as a vehicle serial data bus, meeting the specific requirements of this field: real-time processing, reliable operation in the EMI environment of a vehicle, cost-effectiveness and required bandwidth. The FlexCAN module contains 32 message buffers.

The FlexCAN module provides the following features:

- Full implementation of the CAN protocol specification, version 2.0B
  - Standard data and remote frames
  - Extended data and remote frames
  - Up to 8-bytes data length
  - Programmable bit rate up to 1 Mbit/s
  - 32 message buffers of up to 8-bytes data length
- Each message buffer configurable as Rx or Tx, all supporting standard and extended messages
- · Programmable loop-back mode supporting self-test operation
- 3 programmable mask registers



- Clock frequency same as that used for e200z0h core
- PWM outputs can operate as complementary pairs or independent channels
- Can accept signed numbers for PWM generation
- Independent control of both edges of each PWM output
- Synchronization to external hardware or other PWM supported
- Double buffered PWM registers
  - Integral reload rates from 1 to 16
  - Half cycle reload capability
- Multiple ADC trigger events can be generated per PWM cycle via hardware
- Write protection for critical registers
- Fault inputs can be assigned to control multiple PWM outputs
- Programmable filters for fault inputs
- Independently programmable PWM output polarity
- Independent top and bottom deadtime insertion
- Each complementary pair can operate with its own PWM frequency and deadtime values
- Individual software-control for each PWM output
- All outputs can be programmed to change simultaneously via a "Force Out" event
- PWMX pin can optionally output a third PWM signal from each submodule
- Channels not used for PWM generation can be used for buffered output compare functions
- Channels not used for PWM generation can be used for input capture functions
- Enhanced dual-edge capture functionality
- eDMA support with automatic reload
- 2 fault inputs
- · Capture capability for PWMA, PWMB, and PWMX channels not supported

### 1.5.25 eTimer

The MPC5602P includes one eTimer module which provides six 16-bit general purpose up/down timer/counter units with the following features:

- Clock frequency same as that used for the e200z0h core
- Individual channel capability
  - Input capture trigger
  - Output compare
  - Double buffer (to capture rising edge and falling edge)
  - Separate prescaler for each counter
  - Selectable clock source
  - 0–100% pulse measurement
  - Rotation direction flag (quad decoder mode)
- Maximum count rate
  - External event counting: max. count rate = peripheral clock/2
  - Internal clock counting: max. count rate = peripheral clock
- Counters are:
  - Cascadable
  - Preloadable
- Programmable count modulo
- Quadrature decode capabilities



- Trigger generation unit configurable in sequential mode or in triggered mode
- Each trigger can be appropriately delayed to compensate the delay of external low pass filter
- Double buffered global trigger unit allowing eTimer synchronization and/or ADC command generation
- Double buffered ADC command list pointers to minimize ADC-trigger unit update
- Double buffered ADC conversion command list with up to 24 ADC commands
- · Each trigger capable of generating consecutive commands
- ADC conversion command allows to control ADC channel, single or synchronous sampling, independent result queue selection

### 1.5.28 Nexus Development Interface (NDI)

The NDI (Nexus Development Interface) block is compliant with Nexus Class 1 of the IEEE-ISTO 5001-2003 standard. This development support is supplied for MCUs without requiring external address and data pins for internal visibility. The NDI block is an integration of several individual Nexus blocks that are selected to provide the development support interface for this device. The NDI block interfaces to the host processor and internal busses to provide development support as per the IEEE-ISTO 5001-2003 Nexus Class 1 standard. The development support provided includes access to the MCU's internal memory map and access to the processor's internal registers.

The NDI provides the following features:

- Configured via the IEEE 1149.1
- All Nexus port pins operate at V<sub>DDIO</sub> (no dedicated power supply)
- Nexus Class 1 supports Static debug

### 1.5.29 Cyclic redundancy check (CRC)

The CRC computing unit is dedicated to the computation of CRC off-loading the CPU. The CRC module features:

- Support for CRC-16-CCITT (x25 protocol):  $- x^{16} + x^{12} + x^5 + 1$
- Support for CRC-32 (Ethernet protocol):  $- x^{32} + x^{26} + x^{23} + x^{22} + x^{16} + x^{12} + x^{11} + x^{10} + x^8 + x^7 + x^5 + x^4 + x^2 + x + 1$
- Zero wait states for each write/read operations to the CRC CFG and CRC INP registers at the maximum frequency

### 1.5.30 IEEE 1149.1 JTAG controller

The JTAG controller (JTAGC) block provides the means to test chip functionality and connectivity while remaining transparent to system logic when not in test mode. All data input to and output from the JTAGC block is communicated in serial format. The JTAGC block is compliant with the IEEE standard.

The JTAG controller provides the following features:

- IEEE test access port (TAP) interface 4 pins (TDI, TMS, TCK, TDO)
- Selectable modes of operation include JTAGC/debug or normal system operation.
- 5-bit instruction register that supports the following IEEE 1149.1-2001 defined instructions:
  - BYPASS
  - IDCODE
  - EXTEST
  - SAMPLE
  - SAMPLE/PRELOAD
- 5-bit instruction register that supports the additional following public instructions:
  - ACCESS\_AUX\_TAP\_NPC



Port	PCR	Alternate	Functions	Derinherol <sup>3</sup>	I/O	Pad	speed <sup>5</sup>	Р	in
pin	register	function <sup>1,2</sup>	Functions	Peripheral	direction <sup>4</sup>	SRC = 0	SRC = 1	64-pin	100-pin
C[1]	PCR[33]	ALT0 ALT1 ALT2 ALT3 —	GPIO[33] — — — AN[2]	SIUL — — ADC_0	Input only	_	_	19	28
C[2]	PCR[34]	ALT0 ALT1 ALT2 ALT3 —	GPIO[34] — — — AN[3]	SIUL — — ADC_0	Input only	_	_	21	30
C[3]	PCR[35]	ALT0 ALT1 ALT2 ALT3 —	GPIO[35] CS1 — TXD EIRQ[21]	SIUL DSPI_0 — LIN_1 SIUL	I/O O O I	Slow	Medium	_	10
C[4]	PCR[36]	ALT0 ALT1 ALT2 ALT3 —	GPIO[36] CS0 X[1] DEBUG[4] EIRQ[22]	SIUL DSPI_0 FlexPWM_0 SSCM SIUL	I/O I/O O I	Slow	Medium		5
C[5]	PCR[37]	ALT0 ALT1 ALT2 ALT3 —	GPIO[37] SCK — DEBUG[5] EIRQ[23]	SIUL DSPI_0 — SSCM SIUL	I/O I/O — I	Slow	Medium	_	7
C[6]	PCR[38]	ALT0 ALT1 ALT2 ALT3 —	GPIO[38] SOUT B[1] DEBUG[6] EIRQ[24]	SIUL DSPI_0 FlexPWM_0 SSCM SIUL	I/O O - I	Slow	Medium	_	98
C[7]	PCR[39]	ALT0 ALT1 ALT2 ALT3 —	GPIO[39] — A[1] DEBUG[7] SIN	SIUL  FlexPWM_0 SSCM DSPI_0	I/O — — — —	Slow	Medium	_	9
C[8]	PCR[40]	ALT0 ALT1 ALT2 ALT3	GPIO[40] CS1 — CS6	SIUL DSPI_1  DSPI_0	1/O O — O	Slow	Medium	57	91
C[9]	PCR[41]	ALT0 ALT1 ALT2 ALT3	GPIO[41] CS3 — X[3]	SIUL DSPI_2  FlexPWM_0	I/O O — O	Slow	Medium	_	84

### Table 5. Pin muxing (continued)



- <sup>2</sup> Alternate functions are chosen by setting the values of the PCR.PA bitfields inside the SIU module. PCR.PA = 00 → ALT0; PCR.PA = 01 → ALT1; PCR.PA = 10 → ALT2; PCR.PA = 11 → ALT3. This is intended to select the output functions; to use one of the input functions, the PCR.IBE bit must be written to '1', regardless of the values selected in the PCR.PA bitfields. For this reason, the value corresponding to an input only function is reported as "—".
- <sup>3</sup> Module included on the MCU.
- <sup>4</sup> Multiple inputs are routed to all respective modules internally. The input of some modules must be configured by setting the values of the PSMIO.PADSELx bitfields inside the SIUL module.
- <sup>5</sup> Programmable via the SRC (Slew Rate Control) bits in the respective Pad Configuration Register.
- <sup>6</sup> ADC0.AN emulates ADC1.AN. This feature is used to provide software compatibility between MPC5602P and MPC5604P. Refer to ADC chapter of reference manual for more details.



Symbol		Deveneter	O an dittion a		Unit	
		Parameter	Conditions	Min	Max	
V <sub>DD_HV_IOx</sub> <sup>2</sup>	SR	3.3 V/5.0 V input/output supply voltage (supply). Code flash memory supply with $V_{DD_{-}HV_{-}IO3}$ and data flash memory with $V_{DD_{-}HV_{-}IO2}$	_	-0.3	6.0	V
V <sub>SS_HV_IOx</sub>	SR	3.3 V/5.0 V input/output supply voltage (ground). Code flash memory ground with $V_{SS\_HV\_IO3}$ and data flash memory with $V_{SS\_HV\_IO2}$		-0.1	0.1	V
V <sub>DD_HV_OSC</sub>	SR	3.3 V/5.0 V crystal oscillator amplifier	—	-0.3	6.0	V
		supply voltage (supply)	Relative to V <sub>DD_HV_IOx</sub>	-0.3	$V_{DD_HV_IOx} + 0.3$	
V <sub>SS_HV_OSC</sub>	SR	3.3 V/5.0 V crystal oscillator amplifier supply voltage (ground)		-0.1	0.1	V
V <sub>DD_HV_ADC0</sub>	SR	3.3 V/5.0 V ADC_0 supply and high- reference voltage	V <sub>DD_HV_REG</sub> < 2.7 V	-0.3	$V_{DD_{HV_{REG}}} + 0.3$	V
			V <sub>DD_HV_REG</sub> > 2.7 V	-0.3	6.0	
V <sub>SS_HV_ADC0</sub>	SR	3.3 V/5.0 V ADC_0 ground and low- reference voltage	—	-0.1	0.1	V
V <sub>DD_HV_REG</sub>	SR	3.3 V/5.0 V voltage-regulator supply	—	-0.3	6.0	V
		voltage	Relative to V <sub>DD_HV_IOx</sub>	-0.3	$V_{DD_HV_IOx} + 0.3$	
TV <sub>DD</sub>	SR	Slope characteristics on all $V_{DD}$ during power up <sup>3</sup> with respect to ground $(V_{SS})$		3.0 <sup>4</sup>	500 x 10 <sup>3</sup> (0.5 [V/μs])	V/s
V <sub>DD_LV_CORx</sub>	сс	1.2 V supply pins for core logic (supply)	—	-0.1	1.5	V
V <sub>SS_LV_CORx</sub>	SR	1.2 V supply pins for core logic (ground)	_	-0.1	0.1	V
V <sub>IN</sub>	SR	Voltage on any pin with respect to	—	-0.3	6.0	V
		ground (V <sub>SS_HV_IOx</sub> )	Relative to V <sub>DD_HV_IOx</sub>	-0.3	$V_{DD_HV_IOx} + 0.3^5$	
I <sub>INJPAD</sub>	SR	Input current on any pin during overload condition	—	-10	10	mA
I <sub>INJSUM</sub>	SR	Absolute sum of all input currents during overload condition	—	-50	50	mA
T <sub>STG</sub>	SR	Storage temperature	—	-55	150	°C
TJ	SR	Junction temperature under bias	—	-40	150	°C

Table 7. Absolute maximum	ratings <sup>1</sup>	(continued)
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Figure 5. Independent ADC supply (–0.3 V  $\leq$  V\_{DD\_HV\_REG}  $\leq$  6.0 V)

# 3.4 Recommended operating conditions

Table 8. Recommer	nded operating	conditions	(5.0 V	/)
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Symbol		Devenueter	Conditions	Value		
Зутвої		Parameter	Conditions	Min	Max <sup>1</sup>	Unit
V <sub>SS</sub>	SR	Device ground	—	0	0	V
V <sub>DD_HV_IOx</sub> <sup>2</sup>	SR	5.0 V input/output supply voltage	—	4.5	5.5	V
V <sub>SS_HV_IOx</sub>	SR	Input/output ground voltage	_	0	0	V
V <sub>DD_HV_OSC</sub>	V <sub>DD_HV_OSC</sub> SR 5.0 V cryst		—	4.5	5.5	V
		amplifier supply voltage	Relative to V <sub>DD_HV_IOx</sub>	V <sub>DD_HV_IOx</sub> -0.1	$V_{DD_HV_IOx} + 0.1$	
V <sub>SS_HV_OSC</sub>	SR	5.0 V crystal oscillator amplifier reference voltage	—	0	0	V
V <sub>DD_HV_REG</sub>	SR	5.0 V voltage regulator	—	4.5	5.5	V
		supply voltage	Relative to V <sub>DD_HV_IOx</sub>	V <sub>DD_HV_IOx</sub> -0.1	V <sub>DD_HV_IOx</sub> + 0.1	-
V <sub>DD_HV_ADC0</sub>	SR	5.0 V ADC_0 supply and	—	4.5	5.5	V
		nign reference voltage	Relative to V <sub>DD_HV_REG</sub>	V <sub>DD_HV_REG</sub> -0.1	—	



Symbol		Paramotor		Unit			
Sym	501	Falanielei	Min Typ M		Мах		
f <sub>OSC</sub>	SR	Oscillator frequency	4	_	40	MHz	
f <sub>CLK</sub>	SR	Frequency in bypass	—	—	64	MHz	
t <sub>rCLK</sub>	SR	Rise/fall time in bypass	—	_	1	ns	
t <sub>DC</sub>	SR	Duty cycle	47.5	50	52.5	%	

### Table 25. Input clock characteristics

#### **FMPLL** electrical characteristics 3.12

Table 26. FMPLL electrical characteristics

Symbol	c	Parameter		Conditions <sup>1</sup>	Value		Unit
Symbol		Га	rameter	Conditions	Min	Max	Onic
f <sub>ref_crystal</sub> f <sub>ref_ext</sub>	D	PLL reference frequency range <sup>2</sup>		Crystal reference	4	40	MHz
f <sub>PLLIN</sub>	D	Phase detector inp (after pre-divider)	out frequency range	_	4	16	MHz
f <sub>FMPLLOUT</sub>	D	Clock frequency ra	ange in normal mode	-	16	64	MHz
f <sub>FREE</sub>	Ρ	Free-running frequ	lency	Measured using clock division—typically /16	20	150	MHz
t <sub>CYC</sub>	D	System clock perio	bd	—	_	1 / f <sub>SYS</sub>	ns
f <sub>LORL</sub>	D	Loss of reference frequency window <sup>3</sup>		Lower limit	1.6	3.7	MHz
f <sub>LORH</sub>	D			Upper limit	24	56	
f <sub>SCM</sub>	D	Self-clocked mode frequency <sup>4,5</sup>		—	20	150	MHz
C <sub>JITTER</sub>	Т	CLKOUT period Short-term jitter <sup>10</sup>		f <sub>SYS</sub> maximum	-4	4	% f <sub>CLKOUT</sub>
		Jitter	Long-term jitter (average over 2 ms interval)	f <sub>PLLIN</sub> = 16 MHz (resonator), f <sub>PLLCLK</sub> at 64 MHz, 4000 cycles	_	10	ns
t <sub>ipii</sub>	D	PLL lock time <sup>11, 12</sup>		—	_	200	μs
t <sub>dc</sub>	D	Duty cycle of refer	ence	—	40	60	%
f <sub>LCK</sub>	D	Frequency LOCK	range	—	-6	6	% f <sub>SYS</sub>
f <sub>UL</sub>	D	Frequency un-LO	CK range	—	-18	18	% f <sub>SYS</sub>
f <sub>CS</sub>	D	Modulation depth		Center spread	±0.25	±4.0 <sup>13</sup>	% f <sub>SYS</sub>
f <sub>DS</sub>	D	1		Down spread	-0.5	-8.0	1
f <sub>MOD</sub>	D	Modulation freque	ncy <sup>14</sup>	-	—	70	kHz

<sup>1</sup>  $V_{DD\_LV\_CORx} = 1.2 V \pm 10\%$ ;  $V_{SS} = 0 V$ ;  $T_A = -40$  to 125 °C, unless otherwise specified <sup>2</sup> Considering operation with PLL not bypassed.

<sup>3</sup> "Loss of Reference Frequency" window is the reference frequency range outside of which the PLL is in self clocked mode.



to ground. For instance, assuming a conversion rate of 1 MHz, with  $C_S+C_{P2}$  equal to 3 pF, a resistance of 330 k $\Omega$  is obtained ( $R_{EQ} = 1 / (fc \times (C_S+C_{P2}))$ ), where fc represents the conversion rate at the considered channel). To minimize the error induced by the voltage partitioning between this resistance (sampled voltage on  $C_S+C_{P2}$ ) and the sum of  $R_S + R_F$ , the external circuit must be designed to respect the Equation 4:

Eqn. 4

$$V_A \bullet \frac{R_S + R_F}{R_{EO}} < \frac{1}{2}LSB$$

Equation 4 generates a constraint for external network design, in particular on resistive path.



Figure 14. Input equivalent circuit

A second aspect involving the capacitance network shall be considered. Assuming the three capacitances  $C_F$ ,  $C_{P1}$  and  $C_{P2}$  are initially charged at the source voltage  $V_A$  (refer to the equivalent circuit reported in Figure 14): A charge sharing phenomenon is installed when the sampling phase is started (A/D switch closed).



#### 3.14.2 **ADC** conversion characteristics

Symbol		~	Deremeter	Conditional	Value			Unit
		C	Parameter	Conditions	Min	Тур	Max	
f <sub>CK</sub>	SR		ADC clock frequency (depends on ADC configuration) (The duty cycle depends on ADC clock <sup>2</sup> frequency)	_	3 <sup>3</sup>		60	MHz
f <sub>s</sub>	SR		Sampling frequency	—	—	_	1.53	MHz
t <sub>s</sub>		D	Sampling time <sup>4</sup>	f <sub>ADC</sub> = 20 MHz, INPSAMP = 3	125			ns
			f <sub>ADC</sub> = 9 MHz, INPSA				28.2	μs
t <sub>c</sub>	_	Ρ	Conversion time <sup>5</sup>	Conversion time <sup>5</sup> $f_{ADC} = 20 \text{ MHz}^6$ , INPCMP = 1		_		μs
t <sub>ADC_PU</sub>	SR	_	ADC power-up delay (time needed for ADC to settle exiting from software power down; PWDN bit = 0)	_		_	1.5	μs
C <sub>S</sub> <sup>7</sup>	—	D	ADC input sampling capacitance		_		2.5	pF
C <sub>P1</sub> <sup>7</sup>		D	ADC input pin capacitance 1	_	_		3	pF
C <sub>P2</sub> <sup>7</sup>	—	D	ADC input pin capacitance 2	_	_	_	1	pF
$R_{SW}^7$		D	Internal resistance of analog source	$V_{DD_HV_ADC0} = 5 V \pm 10\%$	_		0.6	kΩ
				$V_{DD\_HV\_ADC0} = 3.3 \text{ V} \pm 10\%$	_		3	kΩ
$R_{AD}^{7}$		D	Internal resistance of analog source	—	_		2	kΩ
I <sub>INJ</sub>		Т	Input current injection	Current injection on one ADC input, different from the converted one. Remains within TUE specification	-5		5	mA
INL	СС	Ρ	Integral non-linearity	No overload	-1.5	—	1.5	LSB
DNL	СС	Ρ	Differential non-linearity	No overload	-1.0	—	1.0	LSB
EO	СС	Т	Offset error			±1		LSB
E <sub>G</sub>	СС	Т	Gain error	_	_	±1	-	LSB
TUE	СС	Ρ	Total unadjusted error without current injection	_	-2.5	_	2.5	LSB
TUE	СС	Т	Total unadjusted error with current injection	_	-3		3	LSB

 $V_{DD}$  = 3.3 V to 3.6 V / 4.5 V to 5.5 V,  $T_A$  = -40 °C to  $T_{A MAX}$ , unless otherwise specified and analog input voltage 1 from V<sub>SS\_HV\_ADC0</sub> to V<sub>DD\_HV\_ADC0</sub>. <sup>2</sup> AD\_clk clock is always half of the ADC module input clock defined via the auxiliary clock divider for the ADC.

<sup>3</sup> When configured to allow 60 MHz ADC, the minimum ADC clock speed is 9 MHz, below which the precision is lost.

 $^4$  During the sampling time the input capacitance C<sub>S</sub> can be charged/discharged by the external source. The internal resistance of the analog source must allow the capacitance to reach its final voltage level within ts. After the end of the sampling time ts, changes of the analog input voltage have no effect on the conversion result. Values for the sample clock ts depend on programming.

 $^{5}$  This parameter includes the sampling time t<sub>s</sub>.



Symbol		c	Parameter	Conditions <sup>1</sup>		Value			Unit
		Ŭ				Min	Тур	Мах	•
t <sub>tr</sub>	CC	D	Output transition time output pin <sup>2</sup>	C <sub>L</sub> = 25 pF	$V_{DD} = 5.0 V \pm 10\%$ ,	—	—	4	ns
			FAST configuration $C_L = 50 \text{ pF}$ $PAD3V5V = 0$ $C_L = 50 \text{ pF}$ $SIUL.PCRx.SRC = 1$ $C_L = 100 \text{ pF}$ $C_L = 25 \text{ pF}$ $V_{DD} = 3.3 \text{ V} \pm 10\%$	—	—	6			
				C <sub>L</sub> = 100 pF		_	_	12	
				C <sub>L</sub> = 25 pF	V <sub>DD</sub> = 3.3 V ± 10%, PAD3V5V = 1 SIUL.PCRx.SRC = 1	—	—	4	
				C <sub>L</sub> = 50 pF		_	—	7	
				C <sub>L</sub> = 100 pF		_	—	12	
t <sub>SYM</sub> <sup>3</sup>	CC	Т	Symmetric transition time, same drive	$V_{DD}$ = 5.0 V ±	10%, PAD3V5V = 0	—	—	4	ns
			strength between N and P transistor	V <sub>DD</sub> = 3.3 V ±	10%, PAD3V5V = 1	—	—	5	

#### Table 34. Output pin transition times (continued)

 $\label{eq:VDD} \begin{array}{l} 1 \\ V_{DD} = 3.3 \ V \pm 10\% \ / \ 5.0 \ V \pm 10\%, \ T_A = -40 \ ^\circ C \ to \ T_{A \ MAX}, \ unless \ otherwise \ specified. \\ \end{array}$ 

<sup>3</sup> Transition timing of both positive and negative slopes will differ maximum 50%.



Figure 17. Pad output delay

#### AC timing characteristics 3.17

#### **RESET** pin characteristics 3.17.1

The MPC5602P implements a dedicated bidirectional RESET pin.





Figure 26. External interrupt timing

## 3.17.5 DSPI timing

No	No Symbol		C	Parameter	Conditions	Va	Unit		
NO.	Sym	501	C	Falameter	Conditions	Min	Max		
1	t <sub>SCK</sub>	CC	D	DSPI cycle time	Master (MTFE = 0)	60	—	ns	
					Slave (MTFE = 0)	60	—		
2	t <sub>CSC</sub>	CC	D	CS to SCK delay	_	16	—	ns	
3	t <sub>ASC</sub>	СС	D	After SCK delay	_	26	—	ns	
4	t <sub>SDC</sub>	СС	D	SCK duty cycle	_	0.4 * t <sub>SCK</sub>	0.6 * t <sub>SCK</sub>	ns	
5	t <sub>A</sub>	CC	D	Slave access time	SS active to SOUT valid	_	30	ns	
6	t <sub>DIS</sub>	СС	D	Slave SOUT disable time	SS inactive to SOUT high impedance or invalid	—	16	ns	
7	t <sub>PCSC</sub>	CC	D	PCSx to PCSS time	_	13	_	ns	
8	t <sub>PASC</sub>	CC	D	PCSS to PCSx time	_	13	—	ns	
9	t <sub>SUI</sub>	CC	D	Data setup time for inputs	Master (MTFE = 0)	35	—	ns	
					Slave	4	—		
					Master (MTFE = 1, CPHA = 0)	35	—		
					Master (MTFE = 1, CPHA = 1)	35	—		
10	t <sub>HI</sub>	CC	D	Data hold time for inputs	Master (MTFE = 0)	-5	—	ns	
					Slave	4	—		
					Master (MTFE = 1, CPHA = 0)	11	—		
					Master (MTFE = 1, CPHA = 1)	-5	—		

### Table 39. DSPI timing<sup>1</sup>



# 4 Package characteristics

- 4.1 Package mechanical data
- 4.1.1 100 LQFP mechanical outline drawing

	MECHANICAL OUTLIN	ES DOCUM	ENT NO: 98ASS23308
<b>Treescale</b> semiconductor	DICTIONARY	PAGE:	983
© FREESCALE SEMICONDUCTOR, INC. ALL RIGHTS RESERVED. ELECTRONIC VERSIONS ARE UNCONTROLLED EXCEPT WHEN ACCESSED IRECTLY FROM THE DOCUMENT CONTROL REPOSITORY. PRINTED VERSIONS RE UNCONTROLLED EXCEPT WHEN STAMPED "CONTROLLED COPY" IN RED.	DO NOT SCALE THIS DR	AWING REV:	Н
NOTES:			
1. ALL DIMENSIONS ARE IN MILLI	METERS.		
2. INTERPRET DIMENSIONS AND	TOLERANCES PER ASME Y	4.5M-1994.	
3 datums b, c and d to be	DETERMINED AT DATUM PL	ANE H.	
THE TOP PACKAGE BODY SIZE BY A MAXIMUM OF 0.1 MM.	E MAY BE SMALLER THAN	THE BOTTOM P	ACKAGE SIZE
5. DIMENSIONS DO NOT INCLUDE PROTRUSION IS 0.25 mm PE SIZE DIMENSIONS INCLUDING	MOLD PROTRUSIONS. THE R SIDE. THE DIMENSIONS / MOLD MISMATCH.	MAXIMUM ALLO <sup>N</sup> ARE MAXIMUM BO	WABLE ODY
6. DIMENSION DOES NOT INCLUD CAUSE THE LEAD WIDTH TO AND AN ADJACENT LEAD SH.	E DAM BAR PROTRUSION. EXCEED 0.35. MINIMUM SP ALL BE 0.07 MM.	PROTRUSIONS SI ACE BETWEEN P	HALL NOT ROTRUSION
7. DIMENSIONS ARE DETERMINED	AT THE SEATING PLANE.	DATUM A.	
TITLE:	CASE NU	JMBER: 983–02	
TITLE: 100 LEAD LQF	P CASE NU	JMBER: 983-02 RD: NON-JFDFC	

MPC5602P Microcontroller Data Sheet, Rev. 6

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Figure 39. 64 LQFP package mechanical drawing (part 1)





# 6 Document revision history

Table 40 summarizes revisions to this document.

### Table 40. Revision history

Revision	Date	Description of
1	05 Aug 2009	Initial release.
1 2	05 Aug 2009 07 Apr 2010	Initial release. Editorial updates Updated the following items in the "MPC5602P device comparison" table: • The heading • The "SRAM" row • The "FlexCAN" row • The "FlexCAN" row • The "TExPVWI" row • The "LINFlex" row • The "DSPI" row • The "Nexus" row • Deleted the footnote No. 3 Added the "Wakeup unit" block in the MPC5602P block diagram Updated the "Absolute Maximum Ratings" table Updated the "Absolute Maximum Ratings" table Updated the "Absolute Maximum Ratings" table Updated the "Recommended operating conditions (5.0 V)" table Updated the "Recommended operating conditions (3.3 V)" table Updated the "Thermal characteristics for 100-pin LQFP" table: • $\Psi_{J,T}$ changed the typical value Updated the "Ell testing specifications" table: replaced all values in "Level (Max)" column with TBD Updated the "Electrical characteristics" section: • Added the "Introduction" section • Added the "NVUSRO register" section • Added the "Power supplies constraints (-0.3 V ≤ V <sub>DD_HV_REG</sub> ≤ 6.0 V)" figure • Added the "Power supplies constraints (-0.3 V ≤ V <sub>DD_HV_REG</sub> ≤ 6.0 V)" figure • Added the "NVUSRO register" section • Added the "Power supplies constraints (3.0 V < V <sub>DD_HV_REG</sub> ≤ 5.5 V)" figure • Added the "NUSRO register" section • Added the "NVUSRO register" section • Added the "NUSRO register" section • Deleted the "Power supplies constraints (5.0 V, NVUSRO[PAD3V5V] = 0)" section: • Deleted the "Dow sequencing "section • Updated the "DC electrical characteristics" section • Deleted all rows concerning RESET • Delet
2	07 Apr 2010	Added "Appendix A"
(continued)		